

REPLACEMENT OF THE ABSTRACT OF THE DISCLOSURE:

Please replace the Abstract and replace it with the following:

The present invention provides Provided are a device, method and storage medium, ~~stored with software programs, which, when a memory LSI defect analysis apparatus is used as a monitoring device to estimate reductions in yield, can shorten the time needed for full manual interpretation of the obtained results, by~~ interprets interpreting the analyzed results obtained, and calculates calculating the period of distribution patterns and the mix rate of regular patterned defects. ~~First in defect number calculation process 71, the~~ The total defect number of bits is found,; ~~and in factor selection process 61, the factor f_i is then selected. Next, in regular patterned decision process 62, the~~ The value of expected value function, $T(f)$, for the selected f is found, and it is decided whether or not it includes regularly patterned defects; and if it is decided that regularly patterned defects are included (~~process 63~~), then ~~in regular patterned defect mix rate function calculation process 73,~~ regular pattern defect mix rate function $MR(f)$ is calculated from number of bits n , factor f , and the value of estimated value function $T(f)$. If it is decided that it does not contain regularly patterned defects (~~process 65~~), ~~in regular patterned defect mix rate function calculation process 66,~~ the regular patterned defect mix rate function $MR(f)$ is assumed to be zero; and finally, ~~in $MR(f)$ calculation completion confirmation process 67,~~ it is confirmed whether or not $MR(f)$ has been found for every f ; and if there are factors for which $MR(f)$ has not been found, then it returns to process 61.